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using a broadband pulsed mode-locked laser
Cranch, G.A.; Flockhart, G.M.H.; Kirkendall, C.K.;
[Lightwave Technology, Journal of](#)
Volume 23, Issue 11, Nov. 2005 Page(s):3798 - 3807
Digital Object Identifier 10.1109/JLT.2005.857735
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Nakamura, J.; Pain, B.; Nomoto, T.; Nakamura, T.; Fossum, E.R.;
[Electron Devices, IEEE Transactions on](#)
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Digital Object Identifier 10.1109/16.628832
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- ☐ 4. **A 4 M-Pixel CMD image sensor with block and skip access capability**
Nomoto, T.; Hosokai, S.; Isokawa, T.; Hyuga, R.; Nakajima, S.; Terada, T.;
[Electron Devices, IEEE Transactions on](#)
Volume 44, Issue 10, Oct. 1997 Page(s):1738 - 1746
Digital Object Identifier 10.1109/16.628831
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- ☐ 5. **Feasibility study of online high-spatial-resolution MOSFET dosimetry in s**
x-ray radiation fields
Rosenfeld, A.B.; Lerch, M.L.F.; Kron, T.; Brauer-Krisch, E.; Bravin, A.; Holmes-
B.J.;
[Nuclear Science, IEEE Transactions on](#)